

N-Channel 8-V (D-S) MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ)
8	0.047 at V _{GS} = 4.5 V	4.0 ^a	4.24 nC
	0.051 at V _{GS} = 2.5 V	4.0 ^a	
	0.058 at V _{GS} = 1.8 V	4.0 ^a	
	0.069 at V _{GS} = 1.5 V	4.0 ^a	

FEATURES

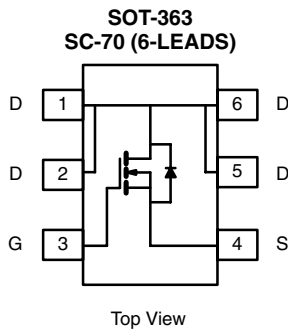
- TrenchFET[®] Power MOSFET: 1.5 V Rated
- 100 % R_g Tested



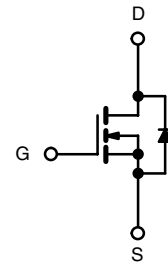
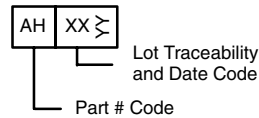
RoHS
COMPLIANT

APPLICATIONS

- Load Switch for Portable Applications
- Guaranteed Operation at V_{GS} = 1.5 V
- Critical for Optimized Design and Space Savings



Marking Code



N-Channel MOSFET

Ordering Information: Si1450DH-T1-E3 (Lead (Pb)-free)

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted				
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	8	V	
Gate-Source Voltage	V _{GS}	± 5		
Continuous Drain Current (T _J = 150 °C)	I _D	T _C = 25 °C	6.04 ^a	
		T _C = 70 °C	4.8 ^a	
		T _A = 25 °C	4.53 ^a	
		T _A = 70 °C	3.62 ^a	
Pulsed Drain Current	I _{DM}	15	A	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C		
		T _A = 25 °C	1.3 ^c	
Maximum Power Dissipation	P _D	T _C = 25 °C	2.78	
		T _C = 70 °C	1.78	
		T _A = 25 °C	1.56 ^{b, c}	
		T _A = 70 °C	1.0 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature) ^{d, e}		260		

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, f}	R _{thJA}	60	80	°C/W	
Maximum Junction-to-Foot (Drain)	R _{thJF}	34	45		

Notes:

- Package limited.
- Surface Mounted on 1" x 1" FR4 Board.
- t = 5 sec.
- Maximum under Steady State conditions is 125 °C/W.

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	8			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250\text{ }\mu\text{A}$		8.32		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			-2.7		
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	0.3		1	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0\text{ V}$, $V_{GS} = \pm 5\text{ V}$			± 100	ns
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 8\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
		$V_{DS} = 8\text{ V}$, $V_{GS} = 0\text{ V}$, $T_J = 55\text{ }^\circ\text{C}$			10	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \leq 5\text{ V}$, $V_{GS} = 4.5\text{ V}$	15			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = 4.5\text{ V}$, $I_D = 4.0\text{ A}$		0.039	0.047	Ω
		$V_{GS} = 2.5\text{ V}$, $I_D = 4.0\text{ A}$		0.042	0.051	
		$V_{GS} = 1.8\text{ V}$, $I_D = 4.0\text{ A}$		0.048	0.058	
		$V_{GS} = 1.5\text{ V}$, $I_D = 1.28\text{ A}$		0.053	0.069	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 4\text{ V}$, $I_D = 4.0\text{ A}$		15.5		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = 4\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$		535		pF
Output Capacitance	C_{oss}			120		
Reverse Transfer Capacitance	C_{rss}			61		
Total Gate Charge	Q_g	$V_{DS} = 4\text{ V}$, $V_{GS} = 5\text{ V}$, $I_D = 4.0\text{ A}$		4.7	7.05	nC
		$V_{DS} = 4\text{ V}$, $V_{GS} = 4.5\text{ V}$, $I_D = 4.0\text{ A}$		4.24	6.4	
Q_{gs}			1.2			
Q_{gd}			0.810			
Gate Resistance	R_g	$f = 1\text{ MHz}$		7.3	11	Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 4\text{ V}$, $R_L = 1.11\text{ }\Omega$ $I_D \cong 3.6\text{ A}$, $V_{GEN} = 4.5\text{ V}$, $R_g = 1\text{ }\Omega$		8	12	ns
Rise Time	t_r			73	110	
Turn-Off Delay Time	$t_{d(off)}$			18	27	
Fall Time	t_f			5	7.5	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$			2.6	A
Pulse Diode Forward Current	I_{SM}				15	
Body Diode Voltage	V_{SD}	$I_S = 2.6\text{ A}$, $V_{GS} = 0\text{ V}$		0.8	1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 2.6\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^\circ\text{C}$		14.3	21.45	ns
Body Diode Reverse Recovery Charge	Q_{rr}			3.6	5.4	nC
Reverse Recovery Fall Time	t_a			6.8		ns
Reverse Recovery Rise Time	t_b			7.5		

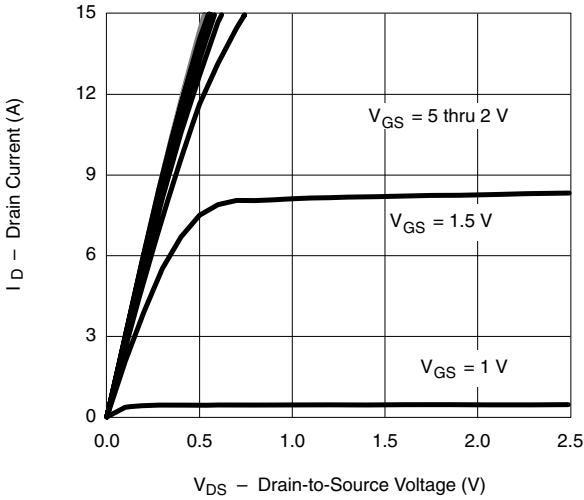
Notes:

a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.

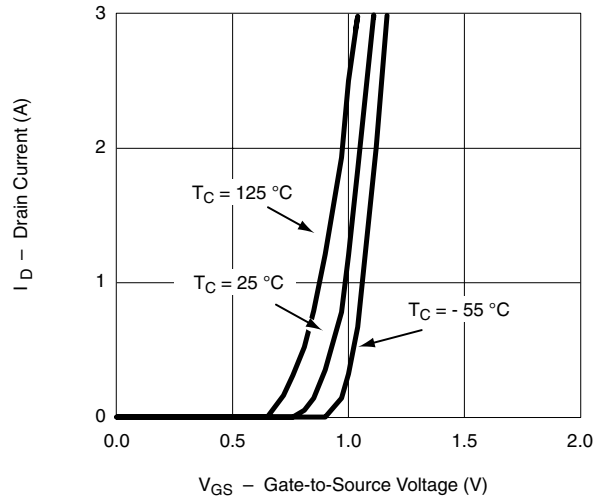
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

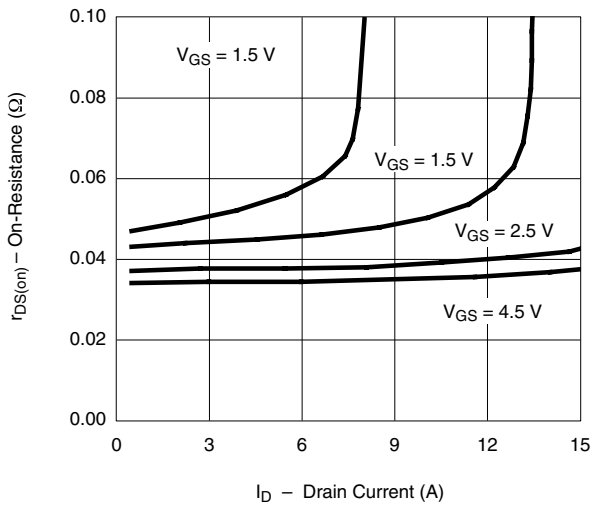
TYPICAL CHARACTERISTICS 25 °C, unless noted



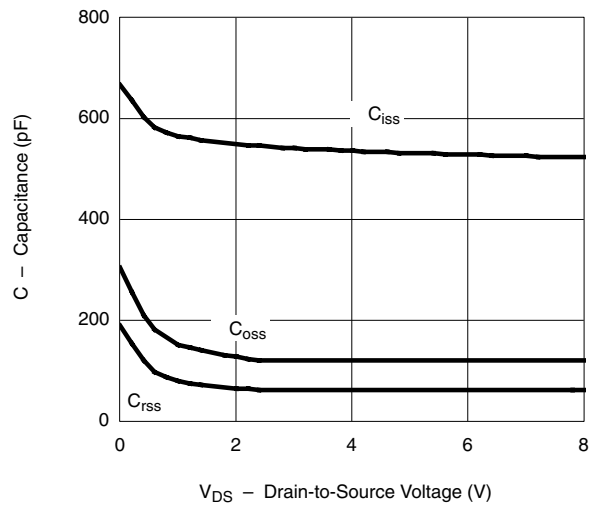
Output Characteristics



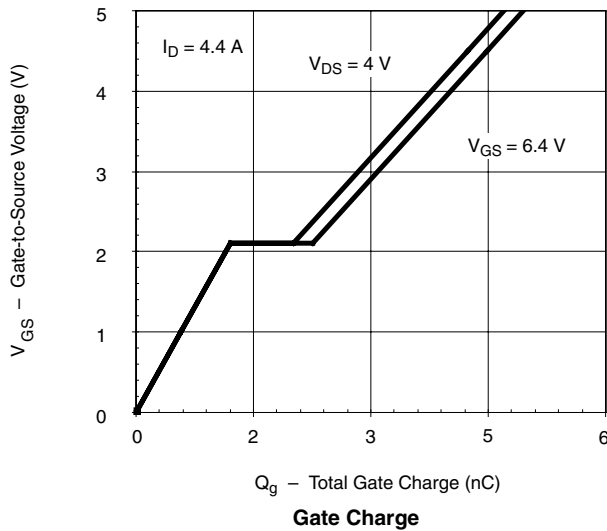
Transfer Characteristics



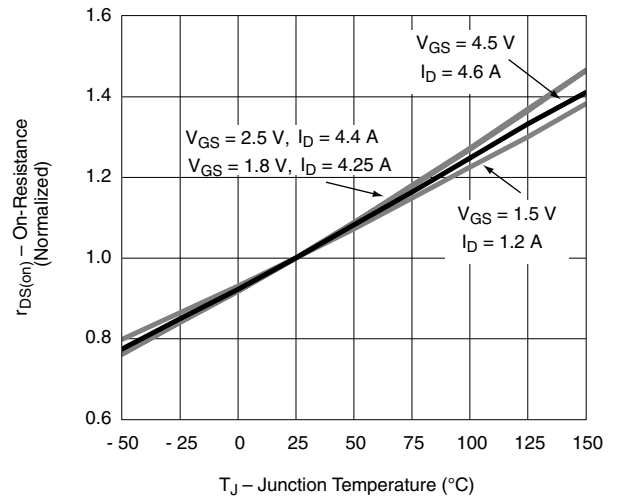
$r_{DS(on)}$ vs. Drain Current



Capacitance

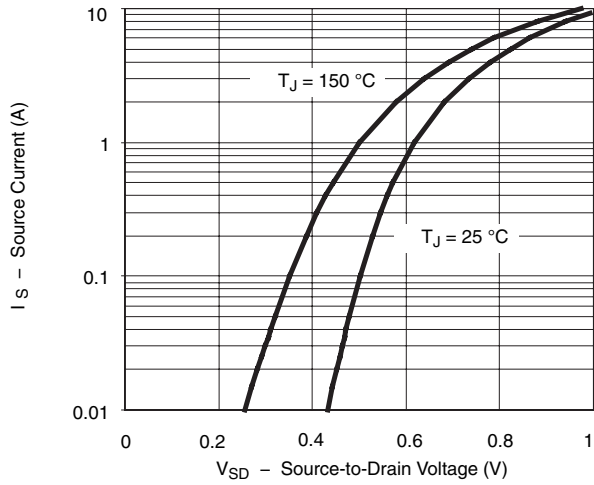


Gate Charge

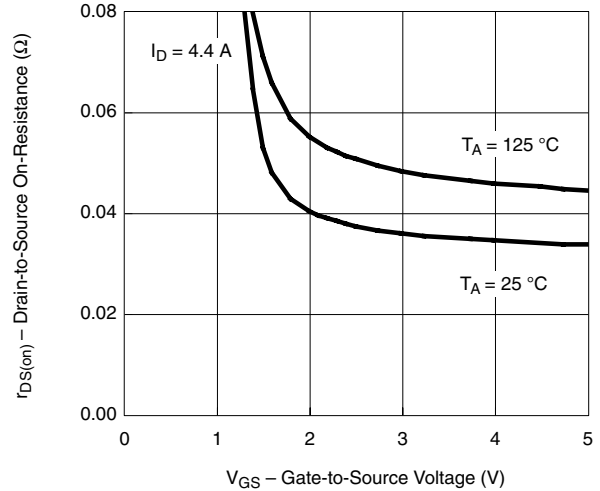


On-Resistance vs. Junction Temperature

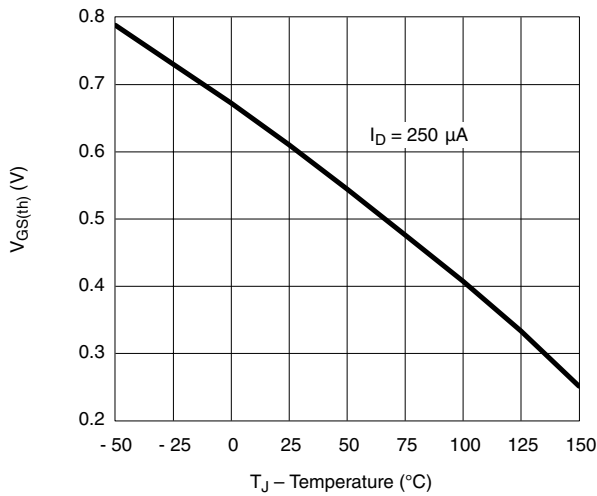
TYPICAL CHARACTERISTICS 25 °C, unless noted



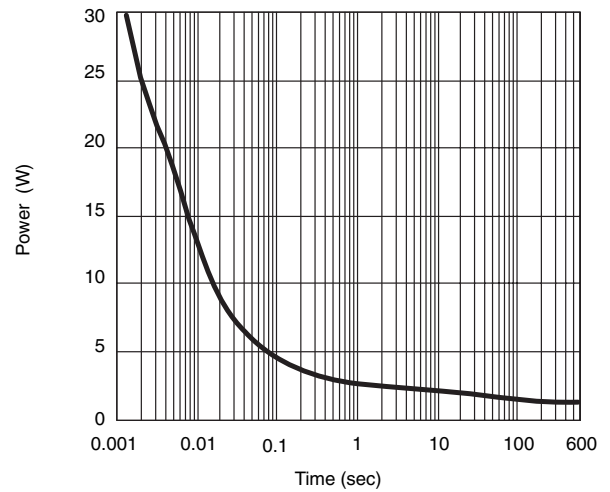
Forward Diode Voltage vs. Temp



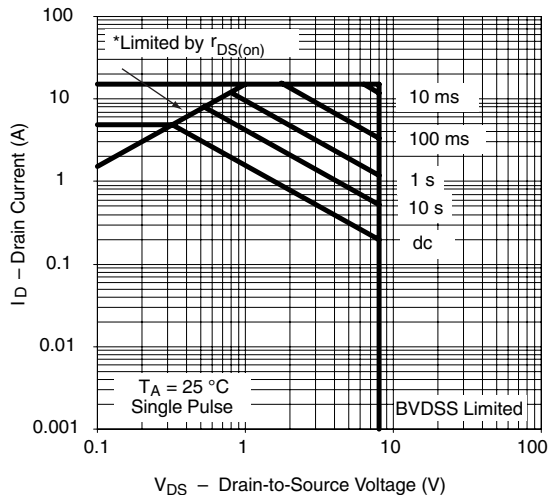
$r_{DS(on)}$ vs. V_{GS} vs. Temperature



Threshold Voltage



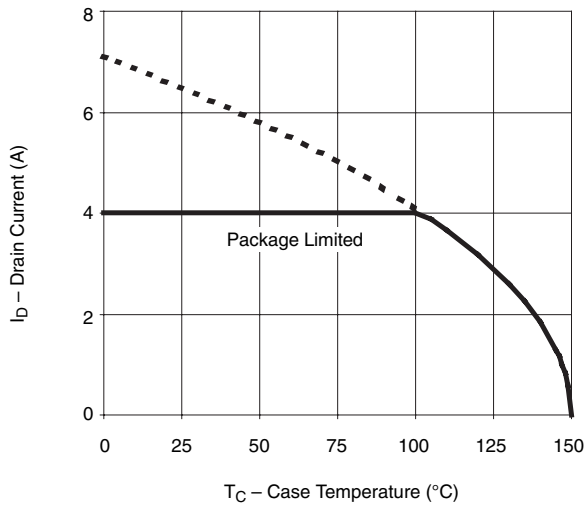
Single Pulse Power



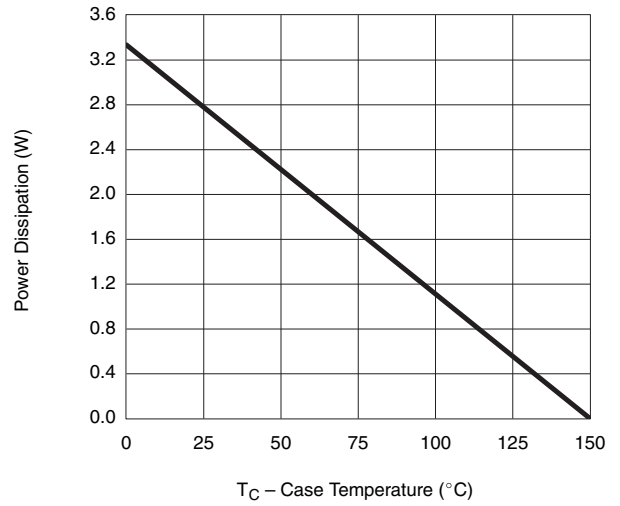
V_{DS} – Drain-to-Source Voltage (V)
 * $V_{GS} >$ minimum V_{GS} at which $r_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Case

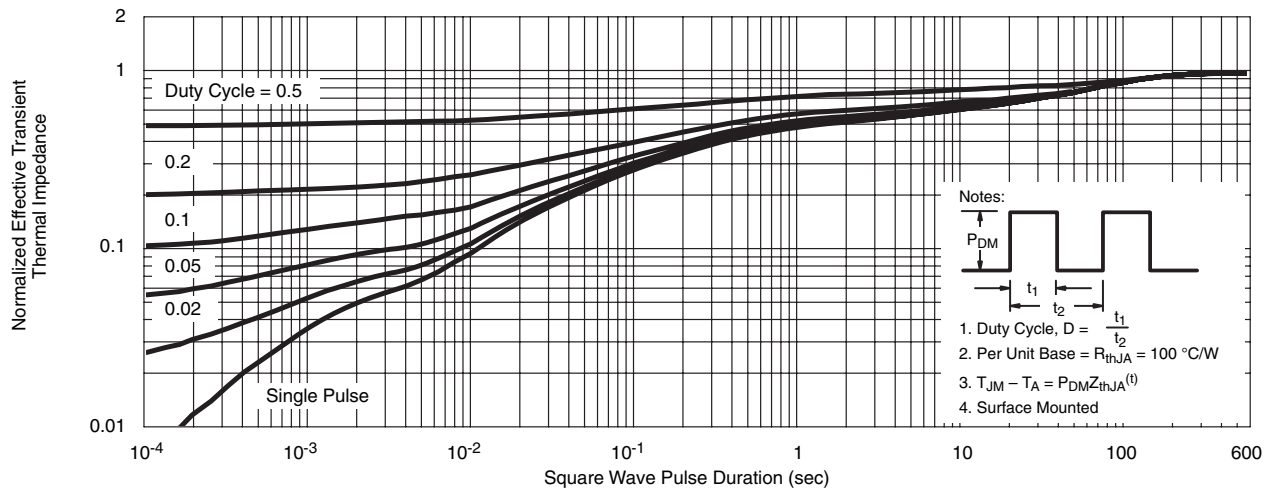
TYPICAL CHARACTERISTICS 25 °C, unless noted



Current Derating*



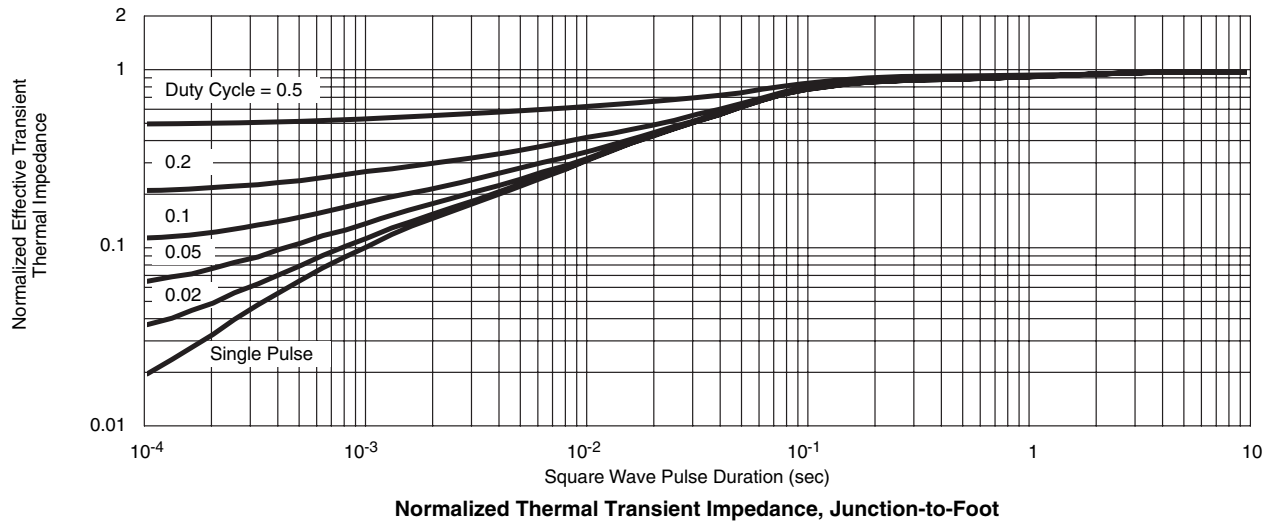
Power Derating



Normalized Thermal Transient Impedance, Junction-to-Ambient

*The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless noted



Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <http://www.vishay.com/ppg?74275>.



Notice

Specifications of the products displayed herein are subject to change without notice. Vishay Intertechnology, Inc., or anyone on its behalf, assumes no responsibility or liability for any errors or inaccuracies.

Information contained herein is intended to provide a product description only. No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document. Except as provided in Vishay's terms and conditions of sale for such products, Vishay assumes no liability whatsoever, and disclaims any express or implied warranty, relating to sale and/or use of Vishay products including liability or warranties relating to fitness for a particular purpose, merchantability, or infringement of any patent, copyright, or other intellectual property right.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications. Customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Vishay for any damages resulting from such improper use or sale.